

## ESD TEST REPORT

<b>Field-Induced Charged-Device Model</b>
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<b>JS-002-2014</b>
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ANSI/ESDA/JEDEC Standard, Method JS-002-2014 is an ESD test using Field-Induced Charged-Device Model, three positive and three negative pulses applied to the devices per customer's specification with 0.5 second cool down between pulses.

**Customer :** Chongqing Alpha and Omega Semiconductor Limited

**Address:** No. 288 Yuefu Road, Beibei District, Chongqing, P.R. China

### Device Information

Part No. :	AOCA24106C	Sample Size :	3pcs
Package Type :	MCSP1.9X1.6	Pin Count :	6
Lot No. :	9C01	Date Code :	-
VDD Domains :	S2 S1	VSS Domains :	S1 S2

### Test Equipment

Tester1 :	ZAPMASTER MK.2 SE	Serial No. :	0508317
Calibration Date :	Jun 20 <sup>th</sup> 2019	Expiration Date :	Jun 19 <sup>th</sup> 2020
Tester2 :	Orion Robotic CDM Test System	Serial No. :	0806294
Calibration Date :	Oct 11 <sup>th</sup> 2019	Expiration Date :	Oct 10 <sup>th</sup> 2020

### Environmental Condition

Temperature :	23°C	Humidity :	30% RH
Submit date :	Dec 27 <sup>th</sup> 2019	Complete date :	Dec 27 <sup>th</sup> 2019


### Stress Summary

CDM			
Sample No.	Voltage Level	Process	Spot Test Results* (Within 10µA @ 8V between G and S2/S1)
9#	±2kV	All Pins Done	PASS
10#		All Pins Done	PASS
11#		All Pins Done	PASS

### Test Result\*

Model	Pin Combinations	ESD Sensitivity Pass*: <b>2kV</b>	V Class: <b>C3</b>
CDM	ALL PINS DONE	±2kV	JS-002-2014 Class C0a: <125V Class C0b: 125V to <250V Class C1: 250 to <500 V Class C2a: 500 to <750 V Class C2b: 750 to <1000 V Class C3: ≥1000V

\*Note: Results will be updated based on customer final electrical test results.

Test Engineer: Wenping Yan	Date: Dec 27 <sup>th</sup> 2019
Approved by Technical Director: 	Date: Dec 27 <sup>th</sup> 2019



### Recommendations

**EAG Shanghai** certifies that above tests have been performed in accordance to the requirements stated above and per the customer purchase order and applicable documents.

**EAG Shanghai** recommends electrical testing as a validation of reported results. Curve Trace criteria was utilized to specify a pass or fail. Industry standards require the device to be tested functionally at post stress and should continue to meet all electrical parameters as per the data sheet.

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